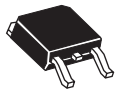


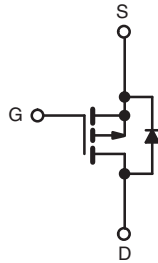
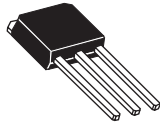
Power MOSFET

| PRODUCT SUMMARY | | |
|---------------------------|------------------|------|
| V_{DS} (V) | - 60 | |
| $R_{DS(on)}$ (Ω) | $V_{GS} = -10$ V | 0.28 |
| Q_g (Max.) (nC) | 19 | |
| Q_{gs} (nC) | 5.4 | |
| Q_{gd} (nC) | 11 | |
| Configuration | Single | |

DPAK
(TO-252)



IPAK
(TO-251)



P-Channel MOSFET

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Surface Mount (IRFR9024/SiHFR9024)
- Straight Lead (IRFU9024/SiHFU9024)
- Available in Tape and Reel
- P-Channel
- Fast Switching
- Lead (Pb)-free Available



RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The DPAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU/SiHFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 W are possible in typical surface mount applications.

| ORDERING INFORMATION | | | | | |
|----------------------|---------------|----------------------------|-----------------------------|-----------------------------|---------------|
| Package | DPAK (TO-252) | DPAK (TO-252) | DPAK (TO-252) | DPAK (TO-252) | IPAK (TO-251) |
| Lead (Pb)-free | IRFR9024PbF | IRFR9024TRPbF ^a | IRFR9024TRLPbF ^a | IRFR9024TRRPbF ^a | IRFU9024PbF |
| | SiHFR9024-E3 | SiHFR9024T-E3 ^a | SiHFR9024TL-E3 ^a | SiHFR9024TR-E3 ^a | SiHFU9024-E3 |
| SnPb | IRFR9024 | IRFR9024TR ^a | IRFR9024TRL ^a | - | IRFU9024 |
| | SiHFR9024 | SiHFR9024T ^a | SiHFR9024TL ^a | - | SiHFU9024 |

Note

- a. See device orientation.

| ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ\text{C}$, unless otherwise noted | | | | |
|--|--------------------------|---------------------------|------------------|---------------------|
| PARAMETER | SYMBOL | | LIMIT | UNIT |
| Drain-Source Voltage | V_{DS} | | - 60 | V |
| Gate-Source Voltage | V_{GS} | | ± 20 | |
| Continuous Drain Current | V_{GS} at -10 V | $T_C = 25^\circ\text{C}$ | - 8.8 | A |
| | | $T_C = 100^\circ\text{C}$ | - 5.6 | |
| Pulsed Drain Current ^a | I_{DM} | | - 35 | W/ $^\circ\text{C}$ |
| Linear Derating Factor | | | 0.33 | |
| Linear Derating Factor (PCB Mount) ^e | | | 0.020 | |
| Single Pulse Avalanche Energy ^b | E_{AS} | | 300 | mJ |
| Repetitive Avalanche Current ^a | I_{AR} | | - 8.8 | A |
| Repetitive Avalanche Energy ^a | E_{AR} | | 5.0 | mJ |
| Maximum Power Dissipation | $T_C = 25^\circ\text{C}$ | | 42 | W |
| Maximum Power Dissipation (PCB Mount) ^e | $T_A = 25^\circ\text{C}$ | | 2.5 | |
| Peak Diode Recovery dV/dt ^c | dV/dt | | - 4.5 | V/ns |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | | - 55 to + 150 | $^\circ\text{C}$ |
| Soldering Recommendations (Peak Temperature) | for 10 s | | 260 ^d | |

Notes


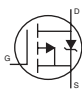
- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = -25$ V, starting $T_J = 25^\circ\text{C}$, $L = 4.5$ mH, $R_G = 25 \Omega$, $I_{AS} = -8.8$ A (see fig. 12).
- $I_{SD} \leq -11$ A, $dI/dt \leq 140$ A/ μs , $V_{DD} \leq V_{DS}$, $T_J \leq 150^\circ\text{C}$.
- 1.6 mm from case.
- When mounted on 1" square PCB (FR-4 or G-10 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply

| THERMAL RESISTANCE RATINGS | | | | | |
|--|------------|------|------|------|------|
| PARAMETER | SYMBOL | MIN. | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient | R_{thJA} | - | - | 110 | °C/W |
| Maximum Junction-to-Ambient (PCB Mount) ^a | R_{thJA} | - | - | 50 | |
| Maximum Junction-to-Case (Drain) | R_{thJC} | - | - | 3.0 | |

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | | |
|--|---------------------|--|--|-------|---------|-----------|---------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$ | | - 60 | - | - | V |
| V_{DS} Temperature Coefficient | $\Delta V_{DS}/T_J$ | Reference to $25\text{ }^\circ\text{C}$, $I_D = 1\text{ mA}$ | | - | - 0.063 | - | V/°C |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ | | - 2.0 | - | - 4.0 | V |
| Gate-Source Leakage | I_{GSS} | $V_{GS} = \pm 20\text{ V}$ | | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = - 60\text{ V}, V_{GS} = 0\text{ V}$ | | - | - | - 100 | μA |
| | | $V_{DS} = - 48\text{ V}, V_{GS} = 0\text{ V}, T_J = 125\text{ }^\circ\text{C}$ | | - | - | - 500 | |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = - 10\text{ V}$ | $I_D = - 5.3\text{ A}^b$ | - | - | 0.28 | Ω |
| Forward Transconductance | g_{fs} | $V_{DS} = - 25\text{ V}, I_D = - 5.3\text{ A}$ | | 2.9 | - | - | S |
| Dynamic | | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}, V_{DS} = - 25\text{ V}, f = 1.0\text{ MHz}$ | | - | 570 | - | pF |
| Output Capacitance | C_{oss} | | | - | 360 | - | |
| Reverse Transfer Capacitance | C_{riss} | | | - | 65 | - | |
| Total Gate Charge | Q_g | $V_{GS} = - 10\text{ V}$ | $I_D = - 11\text{ A}, V_{DS} = - 48\text{ V},$ see fig. 6 and 13 ^b | - | - | 19 | nC |
| Gate-Source Charge | Q_{gs} | | | - | - | 5.4 | |
| Gate-Drain Charge | Q_{gd} | | | - | - | 11 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = - 30\text{ V}, I_D = - 11\text{ A}, R_G = 18\text{ }\Omega, R_D = 2.5\text{ }\Omega,$ see fig. 10 ^b | | - | 13 | - | ns |
| Rise Time | t_r | | | - | 68 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | - | 15 | - | |
| Fall Time | t_f | | | - | 29 | - | |
| Internal Drain Inductance | L_D | Between lead, 6 mm (0.25") from package and center of die contact  | | - | 4.5 | - | nH |
| Internal Source Inductance | L_S | | | - | 7.5 | - | |
| Drain-Source Body Diode Characteristics | | | | | | | |
| Continuous Source-Drain Diode Current | I_S | MOSFET symbol showing the integral reverse p - n junction diode  | | - | - | - 8.8 | A |
| Pulsed Diode Forward Current ^a | I_{SM} | | | - | - | - 35 | |
| Body Diode Voltage | V_{SD} | $T_J = 25\text{ }^\circ\text{C}, I_S = - 8.8\text{ A}, V_{GS} = 0\text{ V}^b$ | | - | - | - 6.3 | V |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25\text{ }^\circ\text{C}, I_F = - 11\text{ A}, di/dt = 100\text{ A}/\mu\text{s}^b$ | | - | 100 | 200 | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | | - | 0.32 | 0.64 | μC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D) | | | | | |

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

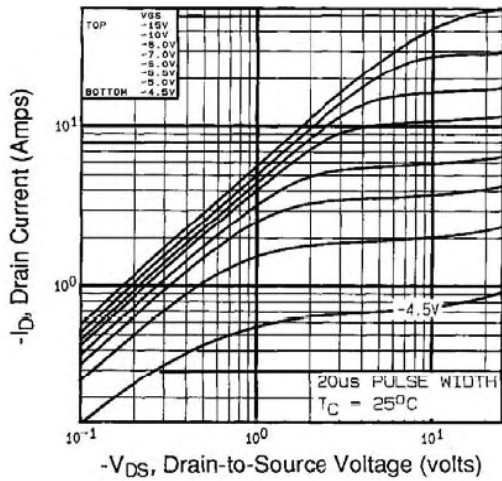


Fig. 1 - Typical Output Characteristics, $T_C = 25^\circ\text{C}$

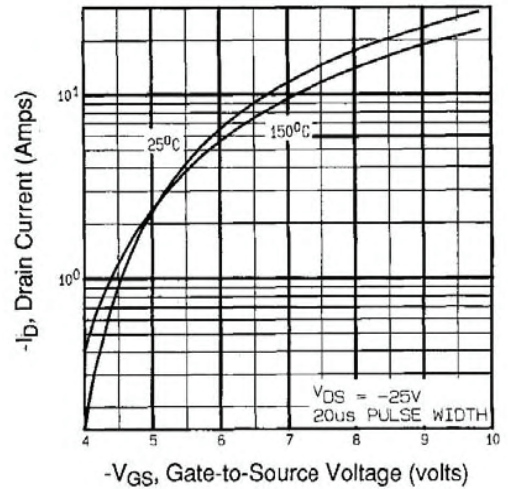


Fig. 3 - Typical Transfer Characteristics

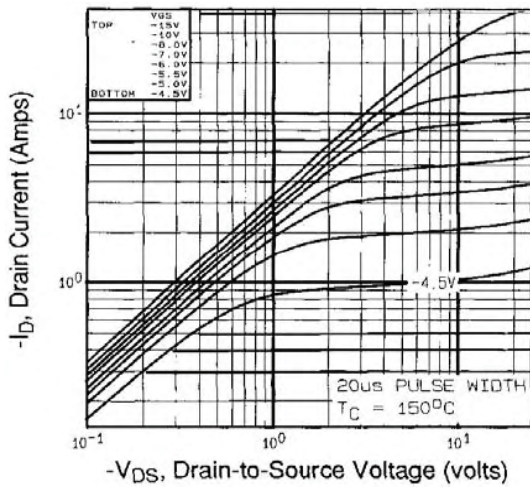


Fig. 2 - Typical Output Characteristics, $T_C = 150^\circ\text{C}$

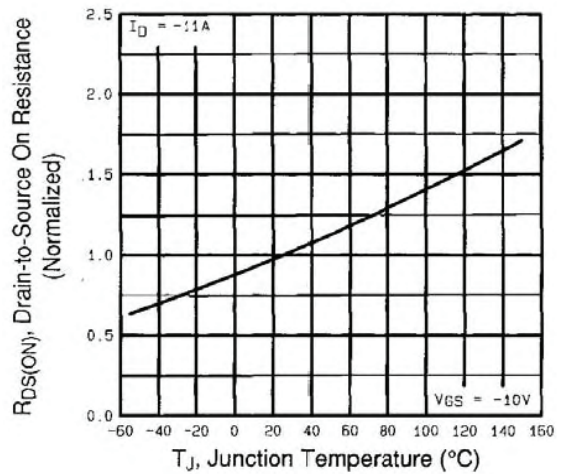


Fig. 4 - Normalized On-Resistance vs. Temperature

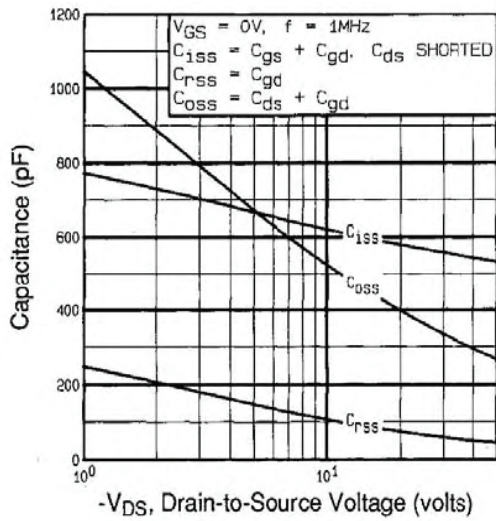


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

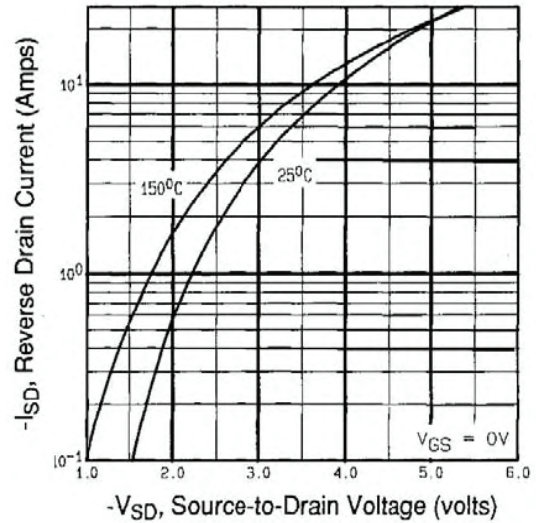


Fig. 7 - Typical Source-Drain Diode Forward Voltage

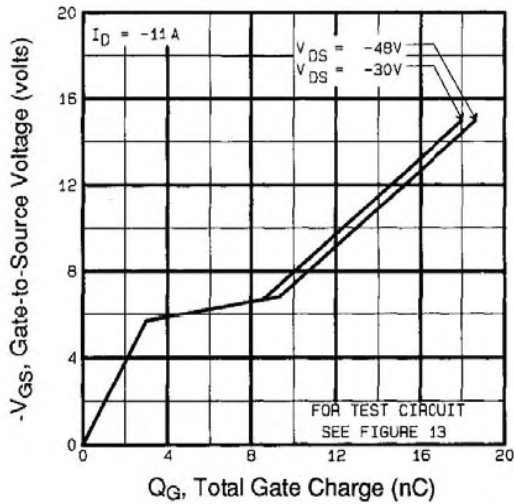


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

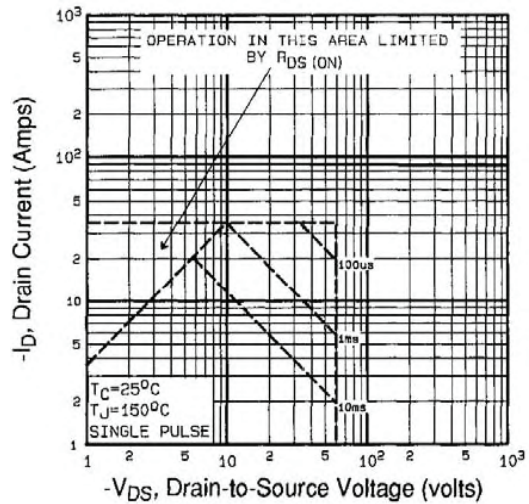


Fig. 8 - Maximum Safe Operating Area

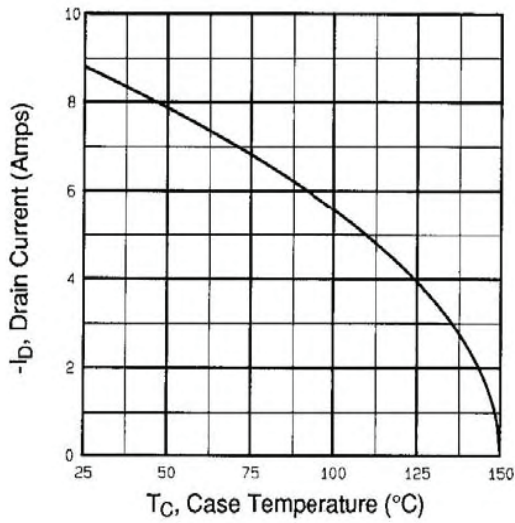


Fig. 9 - Maximum Drain Current vs. Case Temperature

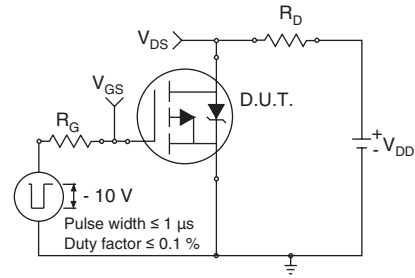


Fig. 10a - Switching Time Test Circuit

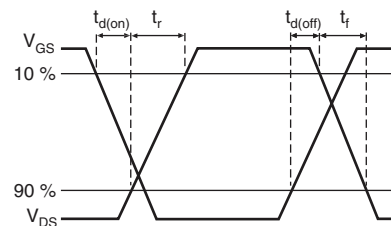


Fig. 10b - Switching Time Waveforms

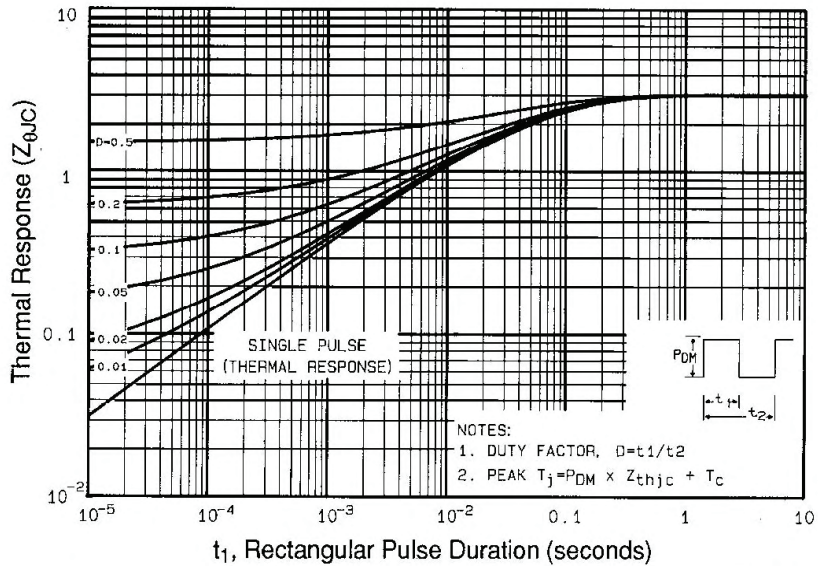


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

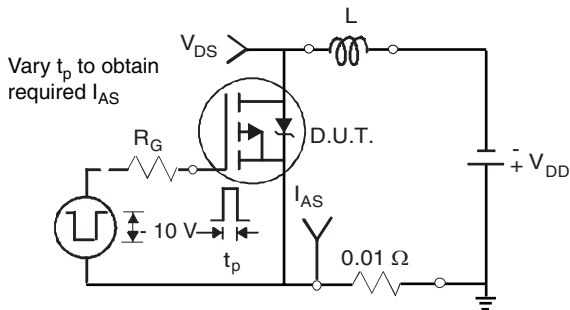


Fig. 12a - Unclamped Inductive Test Circuit

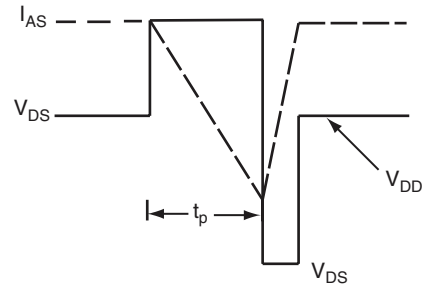


Fig. 12b - Unclamped Inductive Waveforms

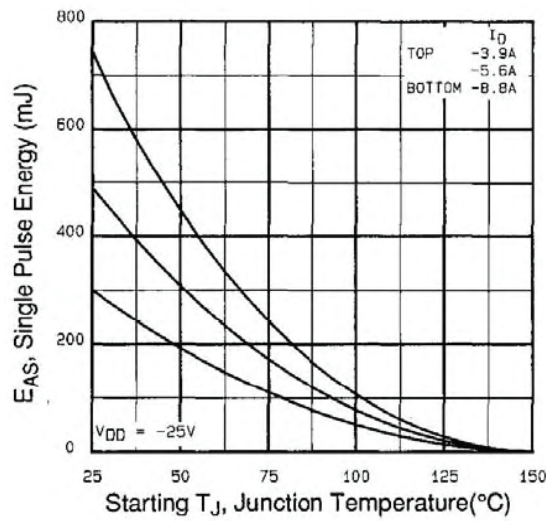


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

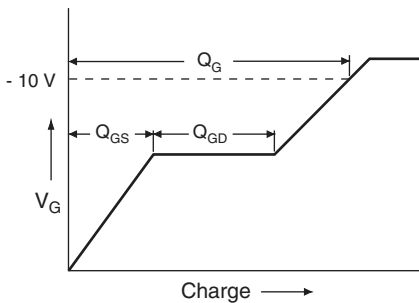


Fig. 13a - Basic Gate Charge Waveform

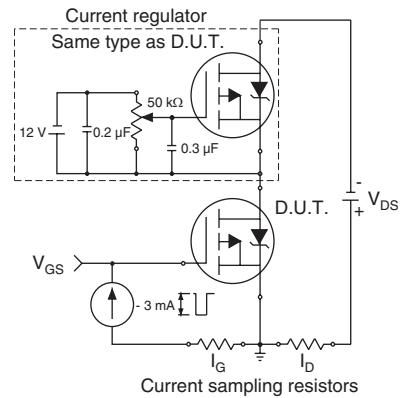
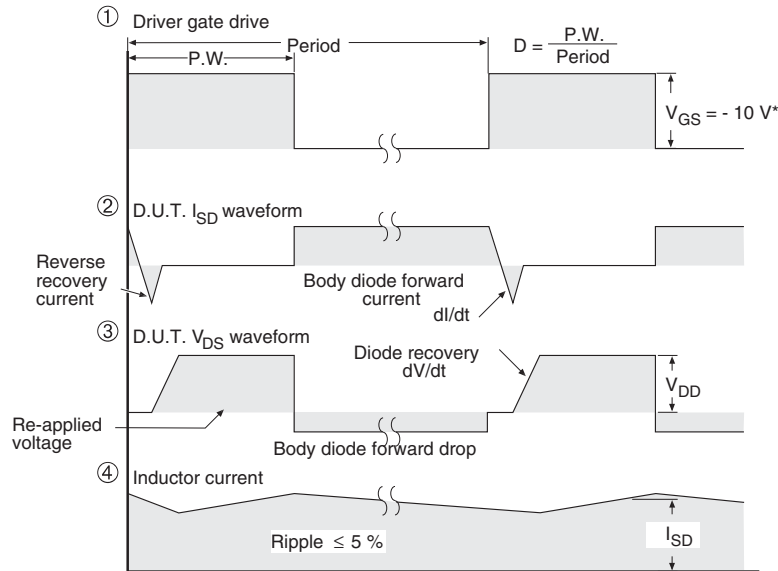
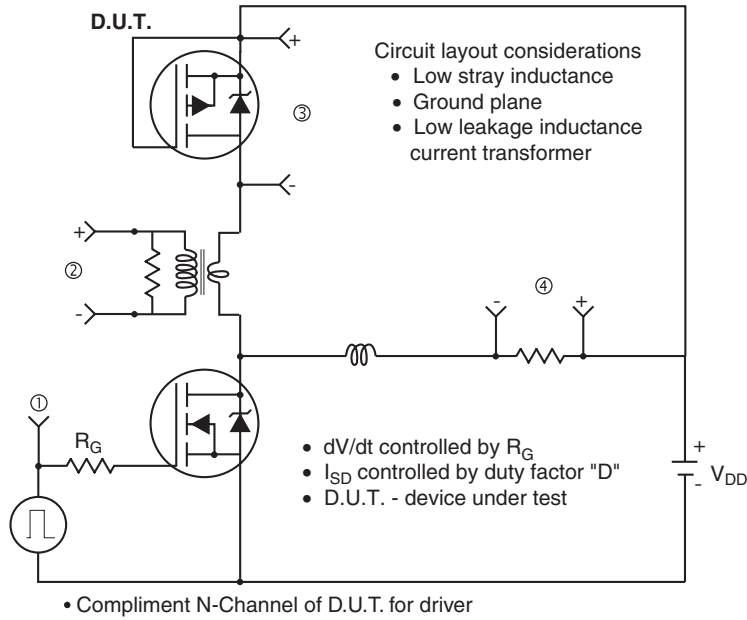


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = -5V$ for logic level and $-3V$ drive devices

Fig. 14 - For P-Channel

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